

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Addressed to: *Applicant(s): Siegel et al.*

*Confirmation No. : 6721*

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

*Serial No. : 10/568,829*

*Group Art Unit: 2831*

*Filed: February 21, 2006*

*Examiner: Unassigned*

*Title: NANOCOMPOSITES WITH CONTROLLED ELECTRICAL PROPERTIES*

**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

This Information Disclosure Statement is being:

<input type="checkbox"/>	submitted together with the application being filed herein; or
<input checked="" type="checkbox"/>	submitted for the first time; or
<input type="checkbox"/>	submitted as a Supplemental Information Disclosure Statement in addition to an Information Disclosure Statement, which was
<input type="checkbox"/>	filed on _____; or
<input type="checkbox"/>	filed together with the application on _____, and such submission is being made:
<input checked="" type="checkbox"/>	under 37 CFR 1.97(b), within three months of filing national application or date of entry of international application, or before mailing date of first office action on the merits, whichever occurs last; or
<input type="checkbox"/>	under 37 CFR 1.97(c) together with either a:
<input type="checkbox"/>	Statement under 37 CFR 1.97(e); or
<input type="checkbox"/>	\$180.00 fee under 37 CFR 1.17(p), after the 37 CFR 1.97(b) time period, but before final action or notice of allowance, whichever occurs first; or
<input type="checkbox"/>	under 37 CFR 1.97(d), filed after final action or notice of allowance, whichever occurs first, but before payment of the issue fee, together with a:
<input type="checkbox"/>	Statement under 37 CFR 1.97(e); and
<input type="checkbox"/>	\$180.00 fee under 37 CFR 1.17(p);
<input checked="" type="checkbox"/>	and, furthermore, please note that this Information Disclosure Statement is being submitted:
<input checked="" type="checkbox"/>	to disclose references cited in the Search Report in a related foreign application; and
<input type="checkbox"/>	within 30 days of receipt of the Search Report (see 37 CFR 1.704(d)).
<input type="checkbox"/>	Comment(s):

Applicant(s) submit herewith an Information Disclosure Citation form listing patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application, and for which there may be a duty to disclose in accordance with 37 CFR 1.56, together with any required copies of the listed references.

It is requested that the information disclosed herein be made of record in this application.

**CERTIFICATE OF MAILING**

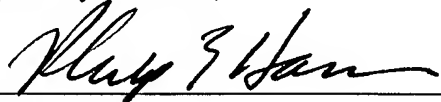
I hereby certify that this correspondence is being deposited with the U.S. Postal Service as first class mail in an envelope addressed to:

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Date of Deposit: October 26, 2006

  
Philip E. Hansen

Respectfully submitted,

  
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<b>INFORMATION DISCLOSURE CITATION</b>	Docket No	0094.064A	Serial No.:	10/568,829
	Applicant(s):	Siegel et al.	Examiner:	Unassigned
	Filing Date:	February 21, 2006	GAU:	2831

**U.S. PATENT DOCUMENTS**

Examiner Initial	Ref	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,228,904	5/8/2001	Yadav et al.			
	AB	6,417,265	7/9/2002	Foulger			
	AC	6,667,368	12/23/2003	Brennan et al.			

**U.S. PATENT APPLICATION PUBLICATIONS**

Examiner Initial	Ref	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

**FOREIGN PATENT DOCUMENTS**

Examiner Initial	Ref	Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	CA	DE 4037972	06.27.1991	Germany				
	CB	WO 00/52712	08.09.2000	PCT				
	CC	WO 02/096982	05.12.2002	PCT				
	CD	WO 2004/038375	06.05.2004	PCT				
	CE	WO 2004/034409	22.04.2004	PCT				

**OTHER DOCUMENTS**

*(Including Author, title, Date, Pertinent Pages, etc.)*

	DA	Onneby et al., "Electrical Properties of Field Grading Materials Influenced by the Silicon Carbide Grain Size," <i>IEEE</i> , pp. 43-45 (2001).
	DB	Martensson et al., "Electrical Properties of Field Grading Materials with Silicon Carbide and Carbon Black," <i>IEEE</i> , pp. 548-552 (1998).

EXAMINER:

Date Considered

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.